

An ionization region model of the reactive Ar/O₂ high power impulse magnetron sputtering discharge

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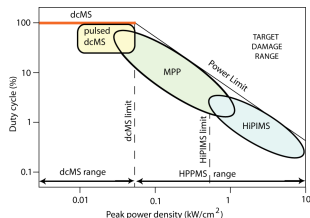
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Introduction

- High ionization of sputtered vapor requires very high density plasma
- In a conventional dc magnetron discharge the power density (plasma density) is limited by the thermal load on the target
- High power pulsed magnetron sputtering (HPPMS)
- In a HiPIMS discharge a high power pulse is supplied for a short period
 - low frequency
 - low duty cycle
 - low average power

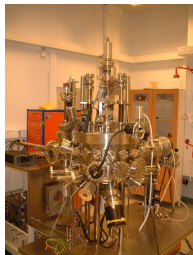


Gudmundsson et al. (2012), JVSTA **30** 030801

- Power density limits
 - $\rho_t = 0.05 \text{ kW/cm}^2$ dcMS limit
 - $\rho_t = 0.5 \text{ kW/cm}^2$ HiPIMS limit

Introduction

- Reactive sputtering, where metal targets are sputtered in a reactive gas atmosphere to deposit compound materials is of utmost importance in various technologies
- In reactive sputtering processes a reactive gas O₂, N₂, or CH₄ etc. is mixed to the noble working gas for oxide, nitride, or carbide deposition
- HiPIMS deposition generally gives denser, smoother films og higher crystallinity than dcMS grown films



Helmersson et al. (2006) Thin Solid Films **513** 1

Magnus et al. (2012) IEEE EDL **33** 1045

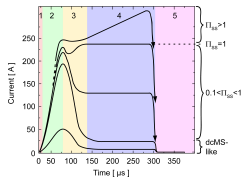


HiPIMS - Voltage - Current - Time characteristics

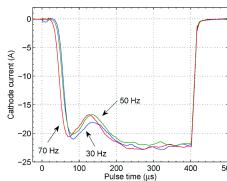


HiPIMS - Voltage - Current - time

- In **non-reactive** discharge the current waveform shows an initial pressure dependent peak that is followed by a second phase that is power and material dependent
- The initial phase is dominated by gas ions, whereas the later phase has a strong contribution from self-sputtering
- The non-reactive case is well understood

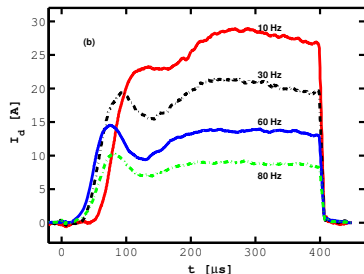


From Gudmundsson et al. (2012), JVSTA 30 030801



HiPIMS - Voltage - Current - time

- During **reactive sputtering**, a reactive gas is added to the inert working gas
- The current waveform in the reactive Ar/N₂ HiPIMS discharge with Ti target is highly dependent on the pulse repetition frequency
- N₂ addition changes the plasma composition and the target condition can also change due to the formation of a compound on its surface

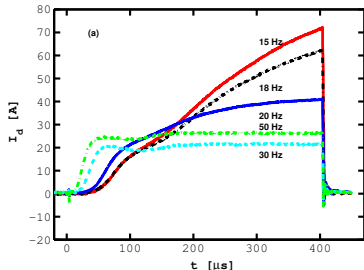


After Magnus et al. (2011) JAP **110** 083306



HiPIMS - Voltage - Current - time

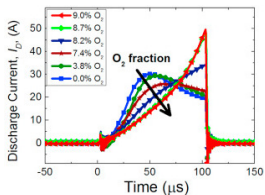
- Similarly for the Ar/O₂ discharge, the current waveform is highly dependent on the repetition frequency and applied voltage which is linked to oxide formation on the target
- The current is found to increase significantly as the frequency is lowered



After Magnus et al. (2012), JVSTA **30** 050601

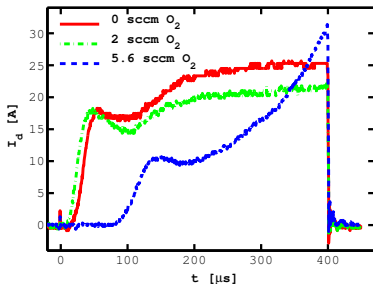
HiPIMS - Voltage - Current - time

- As the oxygen flow is increased a transition to oxide mode is observed



The current waveforms for an Ar/O₂ discharge with a V target where the oxygen flow rate is varied

From Aijaz et al. (2016) Solar Energy Materials and Solar Cells **149** 137

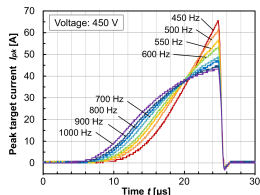
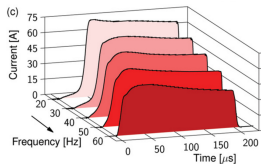


The current waveforms for an Ar/O₂ discharge with a Ti target where the oxygen flow rate is varied – 600 V, 50 Hz and 0.6 Pa

From Gudmundsson et al. (2013), ISSP 2013, p. 192

Gudmundsson (2016) Plasma Phys. Contr. Fus. **58** 014002

HiPIMS - Voltage - Current - time



- Similar behaviour has been reported for various target and reactive gas combinations
 - The current increases with decreased repetition frequency
 - The current waveform maintains its shape for Ar/O₂ discharge with Nb target
- The current waveform becomes distinctly triangular for Ar/N₂ discharge with Hf target

From Hála et al. (2012), JPD **45** 055204

From Shimizu et al. (2016), JPD **49** 065202



HiPIMS - Voltage - Current - time

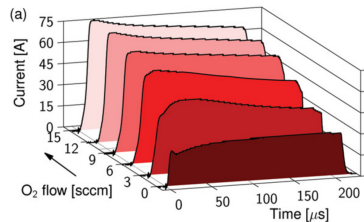
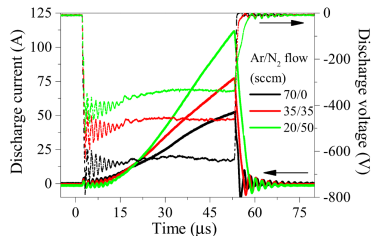
- The current increases with increased partial pressure of the reactive gas

- The current waveform becomes distinctly triangular for Ar/N₂ discharge with Al target

From Moreira et al. (2015), JVSTA **33** 021518

- The current waveform maintains its shape for Ar/O₂ discharge with Nb target

From Hála et al. (2012), JPD **45** 055204

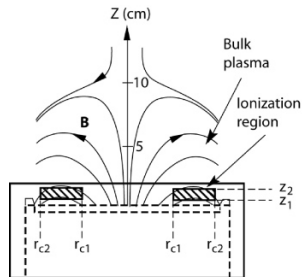


Ionization region model studies of reactive HiPIMS



Ionization region model studies of reactive HiPIMS

- The ionization region model (IRM) was developed to improve the understanding of the plasma behaviour during a HiPIMS pulse and the afterglow
- The main feature of the model is that an ionization region (IR) is defined next to the race track
- The IR is defined as an annular cylinder with outer radii r_{c2} , inner radii r_{c1} and length $L = z_2 - z_1$, extends from z_1 to z_2 axially away from the target



The definition of the volume covered by the IRM

From Raadu et al. (2011), PSST **20** 065007

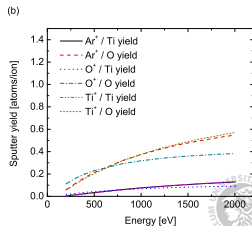
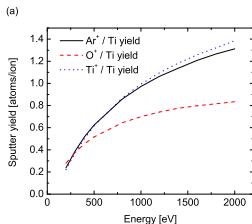


Ionization region model studies of reactive HiPIMS

- The species assumed in the IRM are
 - electrons
 - argon atoms Ar(3s²3p⁶), warm argon atoms in the ground state Ar^W, hot argon atoms in the ground state Ar^H, Ar^m (1s₅ and 1s₃) (11.6 eV), argon ions Ar⁺ (15.76 eV)
 - titanium atoms Ti(a³F), titanium ions Ti⁺ (6.83 eV), doubly ionized titanium ions Ti²⁺ (13.58 eV)
 - oxygen molecule in the ground state O₂(X³Σ_g⁻), the metastable oxygen molecules O₂(a¹Δ_g) (0.98 eV) and O₂(b¹Σ_g) (1.627 eV), the oxygen atom in the ground state O(³P), the metastable oxygen atom O(¹D) (1.96 eV), the positive ions O₂⁺ (12.61 eV) and O⁺ (13.62 eV), and the negative ion O⁻

Ionization region model studies of reactive HiPIMS

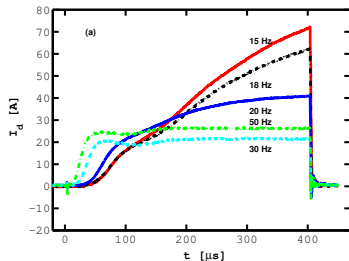
- The sputter yield for the various bombarding ions was calculated by TRIDYN for
 - **Metal mode** – Ti target
 - **Poisoned mode** – TiO₂ target
- The yields correspond to the extreme cases of either clean Ti surface and a surface completely oxidized (TiO₂ surface)
- The sputter yield is much lower for poisoned target



The sputter yield data is from Tomas Kubart, Uppsala University

Ionization region model studies of reactive HiPIMS

- The model is applied to explore Ar/O₂ discharge with Ti target in both metal mode and oxide (poisoned) mode
- The IRM is a semi-empirical model in the sense that it uses a measured discharge current waveform as a main input parameter
- For this study we use the measured curve for Ar/O₂ with Ti target at 50 Hz for metal mode and at 15 Hz for poisoned mode

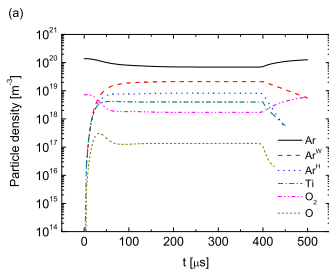


After Magnus et al. (2012), JVSTA **30** 050601



Ionization region model studies of reactive HiPIMS

- The gas rarefaction is observed for the argon atoms but is more significant for the O₂ molecule
- The density of Ti atoms is higher than the O₂ density
- The atomic oxygen density of is over one order of magnitude lower than the molecular oxygen density – the dissociation fraction is low



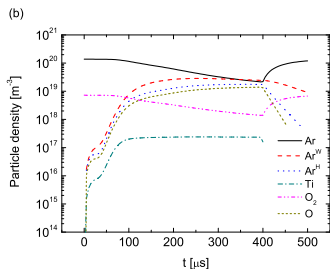
The temporal evolution of the neutral species with 5 % oxygen partial flow rate for Ar/O₂ discharge with Ti target in **metal mode**.

Gudmundsson et al. (2016), PSST, 25(6) 065004



Ionization region model studies of reactive HiPIMS

- Gas rarefaction is observed for both argon atoms and O₂ molecules
- The density of Ti atoms is lower than both the O₂ density and atomic oxygen density
- The atomic oxygen density is higher than the O₂ density towards the end of the pulse

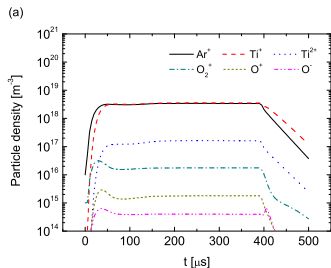


The temporal evolution of the neutral species with **5 % oxygen partial flow** rate for Ar/O₂ discharge with Ti target in **poisoned mode**.

Gudmundsson et al. (2016), PSST, 25(6) 065004

Ionization region model studies of reactive HiPIMS

- Ar⁺ and Ti⁺-ions dominate the discharge
- Ti²⁺-ions follow by roughly an order of magnitude lower density
- The O₂⁺ and O⁺-ion density is much lower



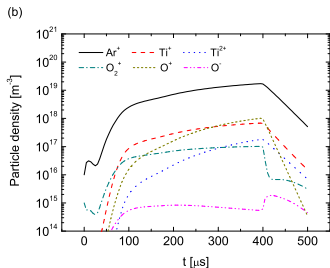
The temporal evolution of the neutral species with **5 % oxygen partial flow** rate for Ar/O₂ discharge with Ti target in **metal mode**.

Gudmundsson et al. (2016), PSST, 25(6) 065004



Ionization region model studies of reactive HiPIMS

- Ar⁺-ions dominate the discharge
- Ti⁺, O⁺, have very similar density, but the temporal variation is different, and the O₂⁺ density is slightly lower
- The Ti²⁺-ion density increases fast with time and overcomes the Ti⁺ density towards the end of the pulse



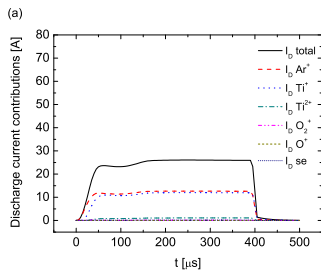
The temporal evolution of the neutral species with **5 % oxygen partial flow** rate for Ar/O₂ discharge with Ti target in **poisoned mode**.

Gudmundsson et al. (2016), PSST, 25(6) 065004



Ionization region model studies of reactive HiPIMS

- Ar⁺ and Ti⁺-ions contribute most significantly to the discharge current

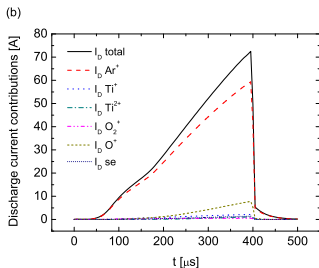


The temporal evolution of the neutral species with **5 % oxygen partial flow rate** for Ar/O₂ discharge with Ti target in **metal mode**.

Gudmundsson et al. (2016), PSST, 25(6) 065004

Ionization region model studies of reactive HiPIMS

- Ar⁺ contribute most significantly to the discharge current – almost solely
- The contribution of secondary electron emission is very small

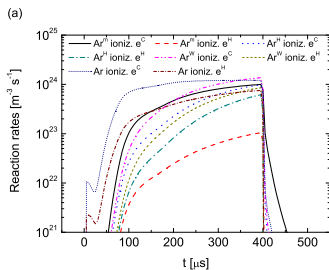


The temporal evolution of the neutral species with **5 % oxygen partial flow rate** for Ar/O₂ discharge with Ti target in **poisoned mode**.

Gudmundsson et al. (2016), PSST, 25(6) 065004

Ionization region model studies of reactive HiPIMS

- Recycling of ionized atoms coming from the target are required for the current generation in both modes of operation
- In the metal mode self-sputter recycling dominates and in the poisoned mode working gas recycling dominates
- The dominating type of recycling determines the discharge current waveform



The temporal variations of the reaction rates for electron impact ionization of the argon atoms (ground state plus metastable) in poisoned mode.

Gudmundsson et al. (2016), PSST, 25(6): 065004



Ionization region model studies of reactive HiPIMS

- In the metal mode sheath energization was found to be only 10 %
 - same range as the results reported earlier for an Al target
Huo et al. (2013), PSST **22**(4) (2013) 045005
- For the poisoned mode the sheath energization was 30 %, with a rising trend, at the end of the pulse
- This is due to the secondary electron emission
 - In the poisoned mode essentially all the ions (mainly Ar⁺, but also O⁺ and Ti²⁺ towards the end of the pulse) contribute to the secondary electron emission
 - In the metal mode only half of the ions contribute to the secondary electron emission (Ar⁺) while the other half does not contribute at all ($\gamma_{\text{Ti}^+} = 0.0$)



Summary



Summary

- An ionization region model was used to explore the plasma composition during the high power pulse
- Comparison was made between the metal mode and the poisoned mode
 - In metal mode Ar⁺ and Ti⁺-ions dominate the discharge and are of the same order of magnitude
 - In poisoned mode Ar⁺-ions dominate the discharge and two orders of magnitude lower, Ti⁺, O⁺, have very similar density, with the O₂⁺ density slightly lower
 - In the metal mode Ar⁺ and Ti⁺-ions contribute most significantly to the discharge current while in poisoned mode Ar⁺ dominate
- In the metal mode self-sputter recycling dominates and in the poisoned mode working gas recycling dominates – the dominating type of recycling determines the discharge current waveform



The slides can be downloaded at

<http://langmuir.raunvis.hi.is/~tumi/ranns.html>

- The experimental work was made in collaboration with
 - Dr. Fridrik Magnus, Uppsala University, Uppsala, Sweden
 - Tryggvi K. Tryggvason, University of Iceland
- We got help with the sputtering yields from
 - Dr. Tomas Kubart, Uppsala University, Uppsala, Sweden
- and the project is funded by
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 - Swedish Government Agency for Innovation Systems (VINNOVA) contract no. 2014-04876,



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